

MOSFET – Power, Single N-Channel, μ8FL 30 V, 5.9 mΩ, 55 A NVTFS4C08N

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- NVTFS4C08NWF Wettable Flanks Product
- NVT Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V _{DSS}	30	V
Gate-to-Source Voltage			V _{GS}	±20	V
Continuous Drain		T _A = 25°C	I _D	17	Α
Current R _{θJA} (Notes 1, 2, 4)		T _A = 100°C		12	
Power Dissipation R _{θJA}		T _A = 25°C	P_{D}	3.1	W
(Note 1, 2, 4)	Steady	T _A = 100°C		1.6	
Continuous Drain Current R _{0JC} (Note 1,	State	T _A = 25°C	I _D	55	
3, 4)		T _A = 100°C		39	Α
Power Dissipation		T _A = 25°C	P_{D}	31	W
R _{θJC} (Note 1, 3, 4)		T _A = 100°C		15	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I _{DM}	253	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	–55 to +175	°C
Source Current (Body Diode)			I _S	28	Α
Single Pulse Drain-to-Source Avalanche Energy ($T_J = 25$ °C, $I_L = 20$ A_{pk} , $L = 0.1$ mH)			E _{AS}	20	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

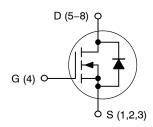
THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Drain) (Notes 1 and 4)	$R_{\theta JC}$	4.9	°C/W
Junction-to-Ambient - Steady State (Notes 1 and 2)	$R_{\theta JA}$	48	C/VV

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm² 2 oz. Cu pad.
- Assumes heat-sink sufficiently large to maintain constant case temperature independent of device power.
- 4. Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX
30.1/	5.9 mΩ @ 10 V	55 A
30 V	9.0 mΩ @ 4.5 V	33 A

N-Channel MOSFET

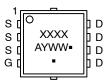


MARKING DIAGRAM



CASE 511AB

WDFNW8 CASE 515AN



4C08 = Specific Device Code for

NVMTS4C08N

08WF = Specific Device Code of

NVTFS4C08NWF

A = Assembly Location

Y = Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

See detailed ordering and shipping information on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

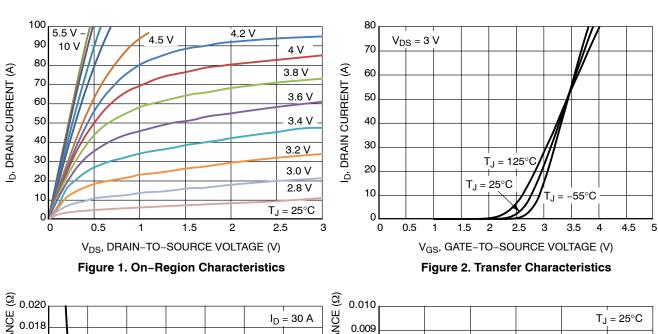
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
OFF CHARACTERISTICS	1						1	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D =$	250 μΑ	30			V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J				13.8		mV/°C	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$	T _J = 25°C			1.0		
		V _{DS} = 24 V	T _J = 125°C			10	μΑ	
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS}$	= ±20 V			±100	nA	
ON CHARACTERISTICS (Note 5)								
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = I_{DS}$	= 250 μΑ	1.3		2.2	V	
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.0		mV/°C	
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		4.7	5.9	0	
		V _{GS} = 4.5 V	I _D = 18 A		7.2	9.0	mΩ	
Forward Transconductance	9 _{FS}	V _{DS} = 1.5 V, I _E	₎ = 15 A		42		S	
Gate Resistance	R_{G}	T _A = 25°	С		1.0		Ω	
CHARGES AND CAPACITANCES								
Input Capacitance	C _{ISS}				1113			
Output Capacitance	Coss	V _{GS} = 0 V, f = 1 MH:	z, V _{DS} = 15 V		702		pF	
Reverse Transfer Capacitance	C _{RSS}				39		1	
Capacitance Ratio	C _{RSS} /C _{ISS}	V _{GS} = 0 V, V _{DS} = 15 V, f = 1 MHz			0.035			
Total Gate Charge	Q _{G(TOT)}				8.4			
Threshold Gate Charge	Q _{G(TH)}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			1.8		nC	
Gate-to-Source Charge	Q_{GS}				3.5			
Gate-to-Drain Charge	Q_{GD}				3.3			
Gate Plateau Voltage	V_{GP}				3.4		V	
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 1	5 V; I _D = 30 A		18.2		nC	
SWITCHING CHARACTERISTICS (Note 6)	, ,	•				•		
Turn-On Delay Time	t _{d(ON)}				9.0			
Rise Time	t _r	$V_{GS} = 4.5 \text{ V}, V_{DS}$	e = 15 V.		33			
Turn-Off Delay Time	t _{d(OFF)}	I _D = 15 A, R _G	= 3.0 Ω		15		ns	
Fall Time	t _f				4.0			
Turn-On Delay Time	t _{d(ON)}				7.0			
Rise Time	t _r	V _{GS} = 10 V, V _{DS}	s = 15 V		26			
Turn-Off Delay Time	t _{d(OFF)}	I _D = 15 A, R _G :	$= 3.0 \Omega$		19		ns	
Fall Time	t _f				3.0			
DRAIN-SOURCE DIODE CHARACTERISTIC	1	1						
Forward Diode Voltage	V_{SD}	V _{GS} = 0 V,	T _J = 25°C		0.79	1.1		
		$I_{S} = 10 \text{ A}$ $I_{J} = 125^{\circ}\text{C}$			0.66		_ v	
Reverse Recovery Time	t _{RR}		<u> </u>		28.3			
Charge Time	t _a	Voo - 0 V dis/d+ -	- 100 A/us		14.5		ns	
Discharge Time	t _b	V_{GS} = 0 V, dIS/dt = 100 A/ μ s, I_S = 30 A			13.8			
Reverse Recovery Charge	Q _{RR}				15.3		nC	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.

6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS



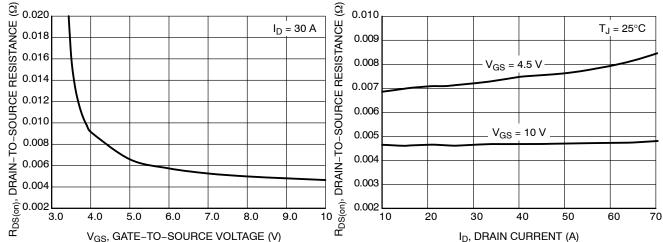
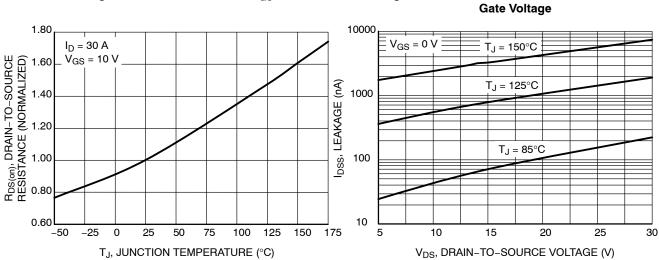


Figure 3. On-Resistance vs. V_{GS}



-25 0 25 50 75 100 125 150 175 5 10 15 20 25 T_J, JUNCTION TEMPERATURE (°C) V_{DS}, DRAIN-TO-SOURCE VOLTAGE (V)

Figure 5. On-Resistance Variation with Temperature Vs. Voltage

Figure 4. On-Resistance vs. Drain Current and

TYPICAL CHARACTERISTICS

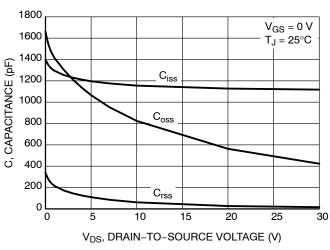


Figure 7. Capacitance Variation

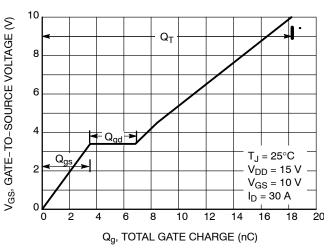


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

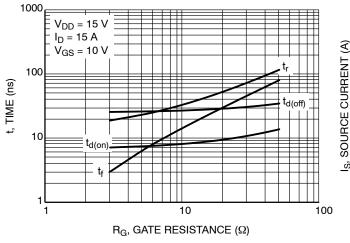


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

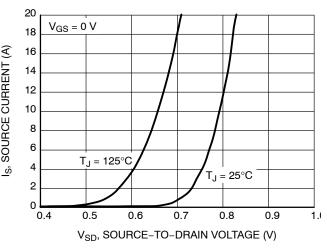


Figure 10. Diode Forward Voltage vs. Current

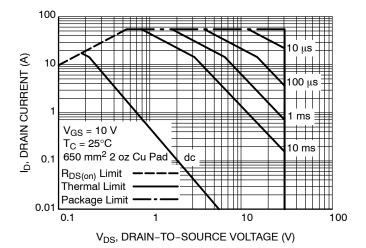


Figure 11. Maximum Rated Forward Biased Safe Operating Area

TYPICAL CHARACTERISTICS

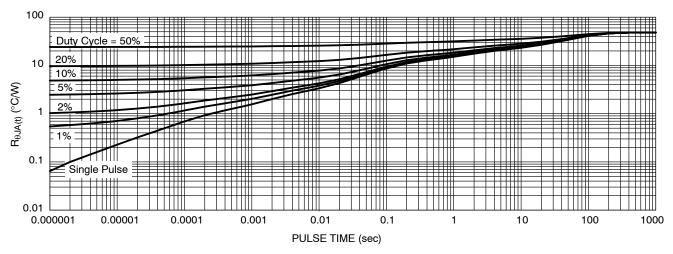


Figure 12. Thermal Response

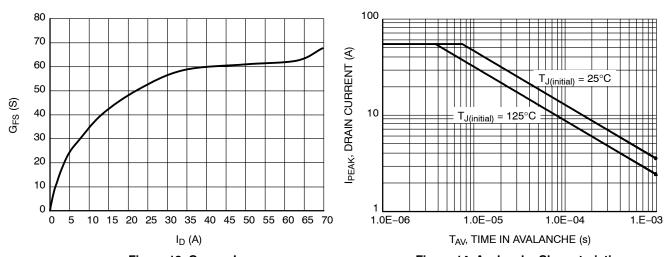


Figure 13. G_{FS} vs. I_D

Figure 14. Avalanche Characteristics

ORDERING INFORMATION

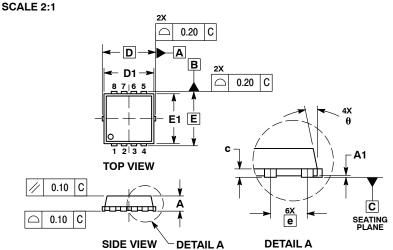
Device	Package	Shipping [†]
NVTFS4C08NTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel
NVTFS4C08NWFTAG	WDFNW8 (Pb-Free)	1500 / Tape & Reel
NVTFS4C08NTWG	WDFN8 (Pb-Free)	5000 / Tape & Reel
NVTFS4C08NWFTWG	WDFNW8 (Pb-Free)	5000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D

DATE 23 APR 2012



NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETERS.
 DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH
 PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.70	0.75	0.80	0.028	0.030	0.031
A1	0.00		0.05	0.000		0.002
b	0.23	0.30	0.40	0.009	0.012	0.016
С	0.15	0.20	0.25	0.006	0.008	0.010
D		3.30 BSC		0	.130 BSC	;
D1	2.95	3.05	3.15	0.116	0.120	0.124
D2	1.98	2.11	2.24	0.078	0.083	0.088
E		3.30 BSC		0	.130 BSC	;
E1	2.95	3.05	3.15	0.116	0.120	0.124
E2	1.47	1.60	1.73	0.058	0.063	0.068
E3	0.23	0.30	0.40	0.009	0.012	0.016
е		0.65 BSC	;	(0.026 BS	0
G	0.30	0.41	0.51	0.012	0.016	0.020
K	0.65	0.80	0.95	0.026	0.032	0.037
L	0.30	0.43	0.56	0.012	0.017	0.022
L1	0.06	0.13	0.20	0.002	0.005	0.008
М	1.40	1.50	1.60	0.055	0.059	0.063
θ	0 °		12 °	0 °		12 °



GENERIC MARKING DIAGRAM*

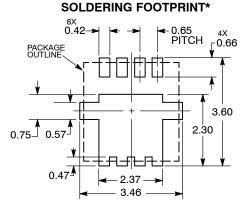


XXXXX = Specific Device Code = Assembly Location

= Year WW = Work Week = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking.

Pb-Free indicator, "G" or microdot " ■", may or may not be present.



DIMENSION: MILLIMETERS

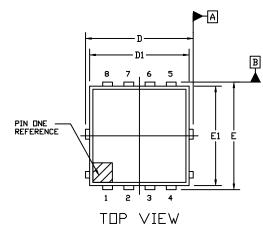
*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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DESCRIPTION:	WDFN8 3.3X3.3, 0.65P		PAGE 1 OF 1

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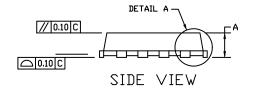


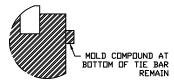
NDTES:

- 1. DIMENSIONING AND TOLERANCING PER.ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- DIMENSION D1 AND E1 D0 NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

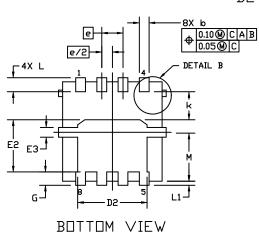
	PLATED AREA
DETAIL	C C SEATING PLANE

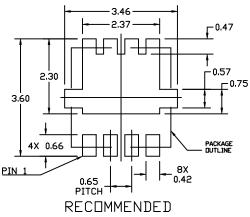
	MILLIMETERS			
DIM	MIN.	NDM.	MAX.	
A	0.70	0.75	0.80	
A1	0.00		0.05	
ø	0.23	0.30	0.40	
n	0.15	0.20	0.25	
D	3.05	3.30	3.55	
D1	2.95	3.05	3.15	
D2	1.98	2.11	2.24	
Ε	3.05	3.30	3.55	
E1	2.95	3.05	3.15	
E2	1.47	1.60	1.73	
E3	0.23	0.30	0.40	
a		0.65 BSC		
G	0.30	0.41	0.51	
K	0.65	0.80	0.95	
٦	0.30	0.43	0.59	
L1	0.06	0.13	0.20	
М	1.40	1.50	1.60	





DETAIL B





MOUNTING FOOTPRINT

For additional information on our Pb-Free strategy and soldering details, please download the DN Semiconductor Soldering and Mounting Techniques Reference Manual, SDLDERRM/D.

GENERIC MARKING DIAGRAM*



XXXX = Specific Device Code

A = Assembly Location

Y = Year

WW = Work Week

= Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

(Note: Microdot may be in either location)

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DESCRIPTION:	WDFNW8 3.3x3.3, 0.65P (F	WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF)	

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